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CCS L56

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 21381-2018

Test method for time dependent dielectric breakdown (TDDB)

时间相关介质击穿(TDDB)测试方法

(English Translation)

Issued by: Ministry of Industry and Information Technology

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1 Foreword

SJ 21381-2018 was issued by Ministry of Industry and Information Technology on 18 January 2018.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 11 pages in English translation.

2 Scope Preview

SJ 21381-2018 is filed under Chinese Standard Classification L56, in the field of electronic components and information technology.

This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

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3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 11 pages (approximate)

Chinese original: about 17,136 characters

4 Related standards

Standards on related subjects:

SJ/T 11890-2023 - Design requirement of energy conservation for LED displays

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

SJ 21382-2018 - Ion implantation uniformity test method

SJ 21380-2018 - Hot carrier effect test method

SJ 21379-2018 - Electromigration effect test method

5 Classification and status

Chinese Standard Classification (CCS): L 56

Prefix SJ: mandatory standard.

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